

**Title: PROBE TESTING METHOD AND APPARATUS FOR DETERMINING ACCEPTABLE/DEFECTIVE END SHAPE OF CONTACT PROBE THROUGH IMAGE ANALYSIS**

Inventor(s): Yoshihiro SASAKI, et al.  
DOCKET NO.: 040373-0338

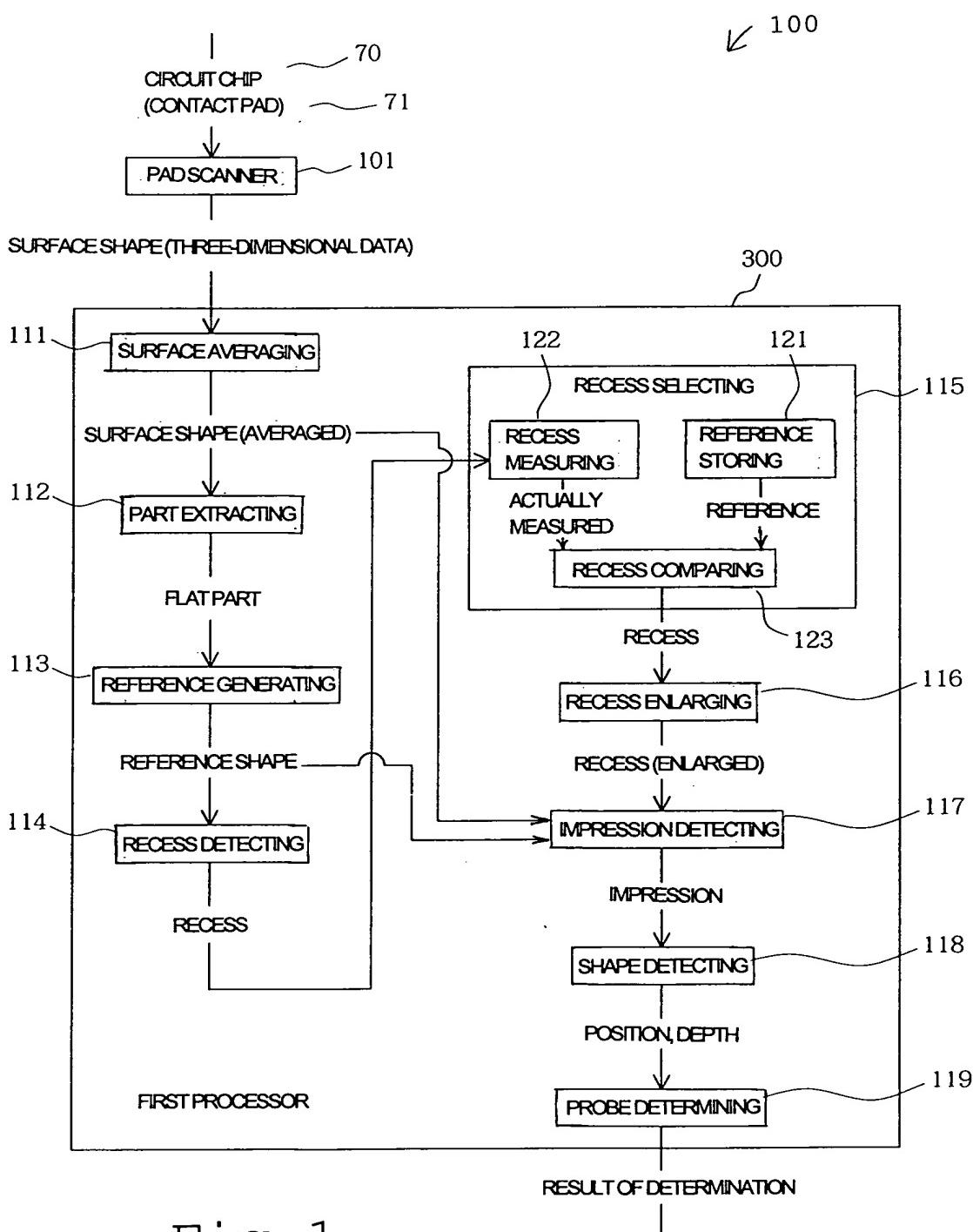


Fig. 1

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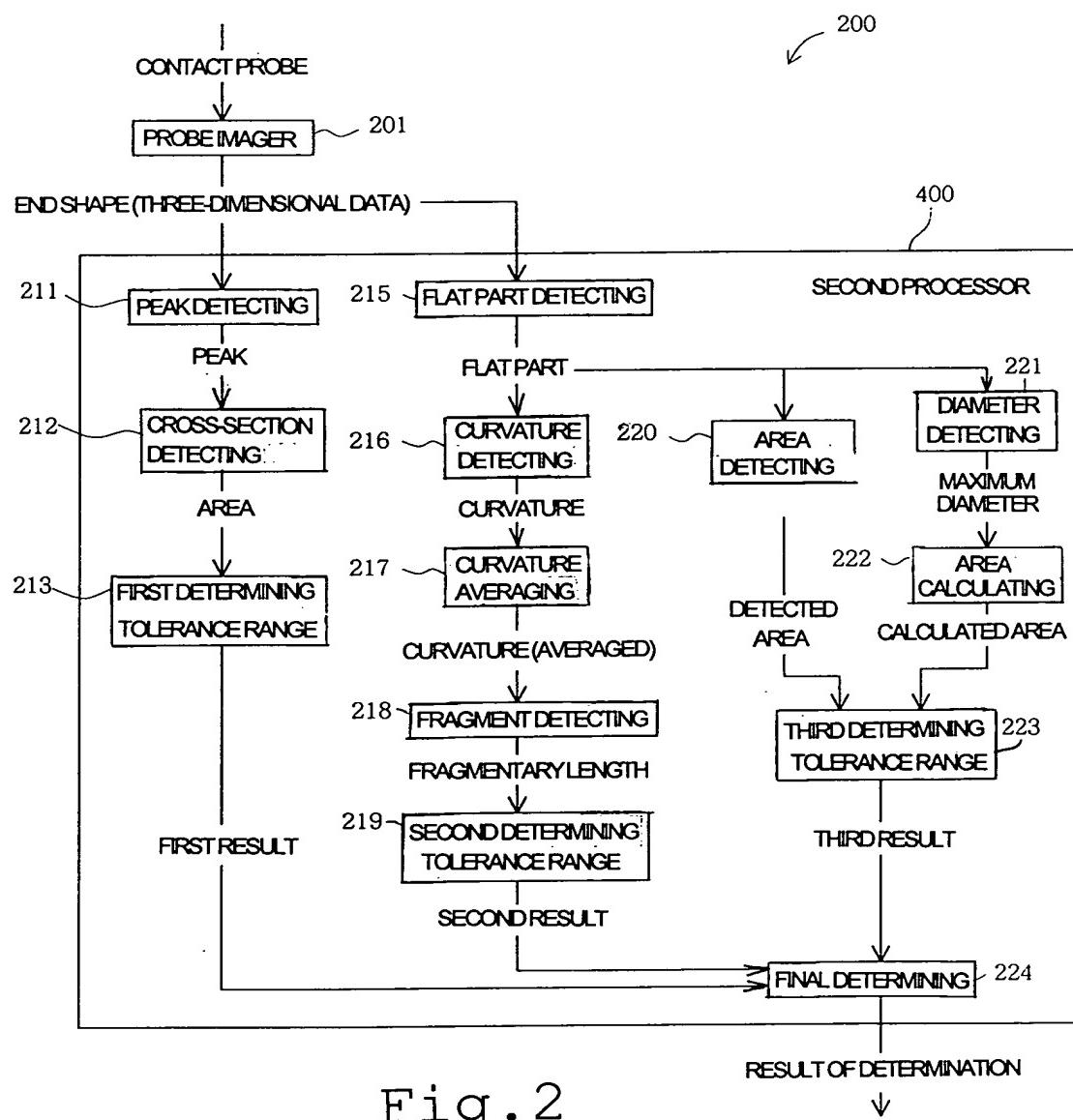


Fig. 2

Fig. 3

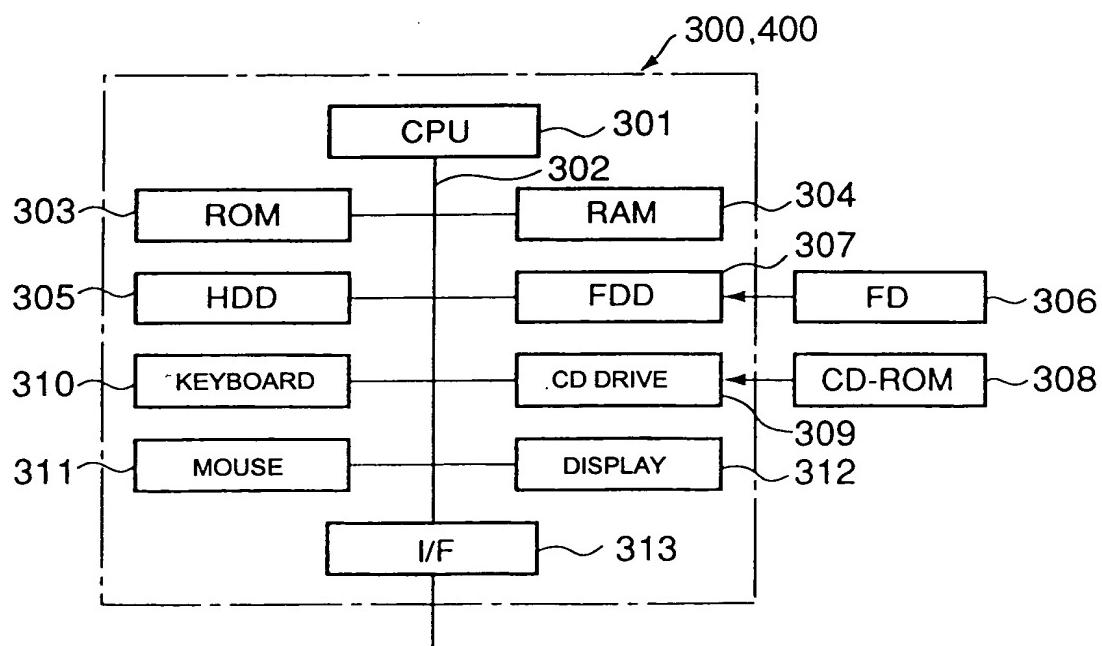
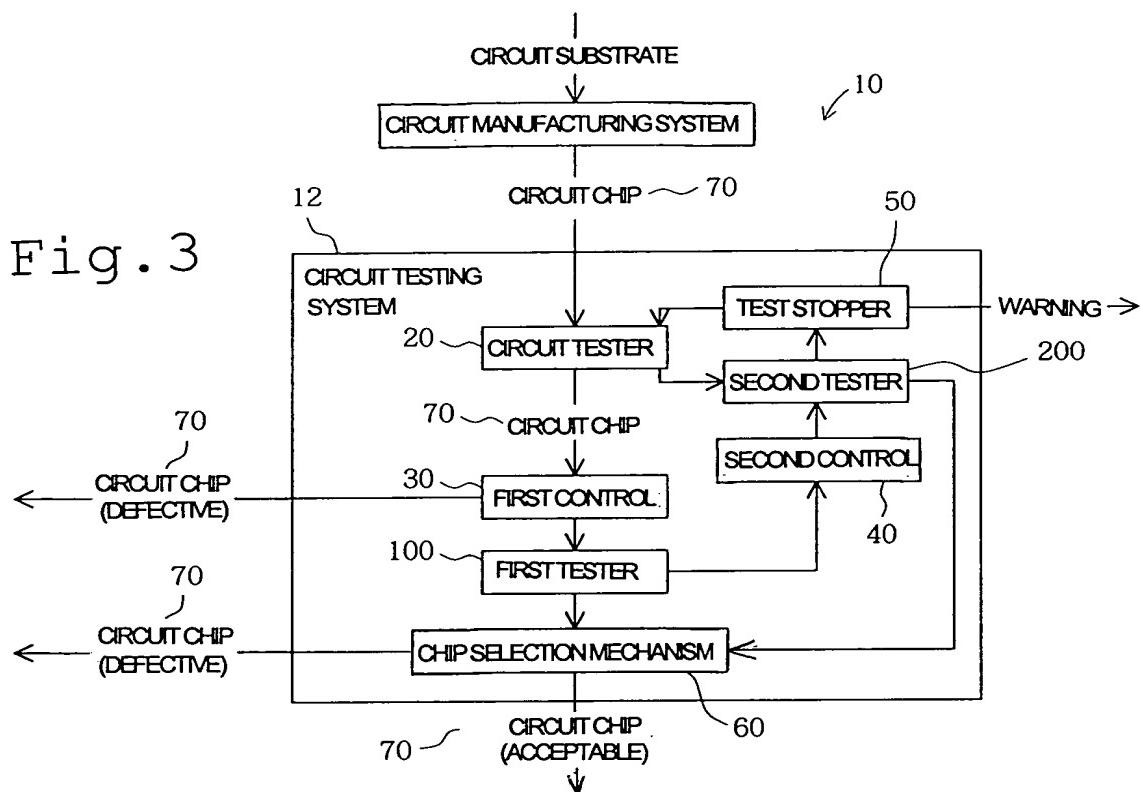


Fig. 4

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Fig.5a

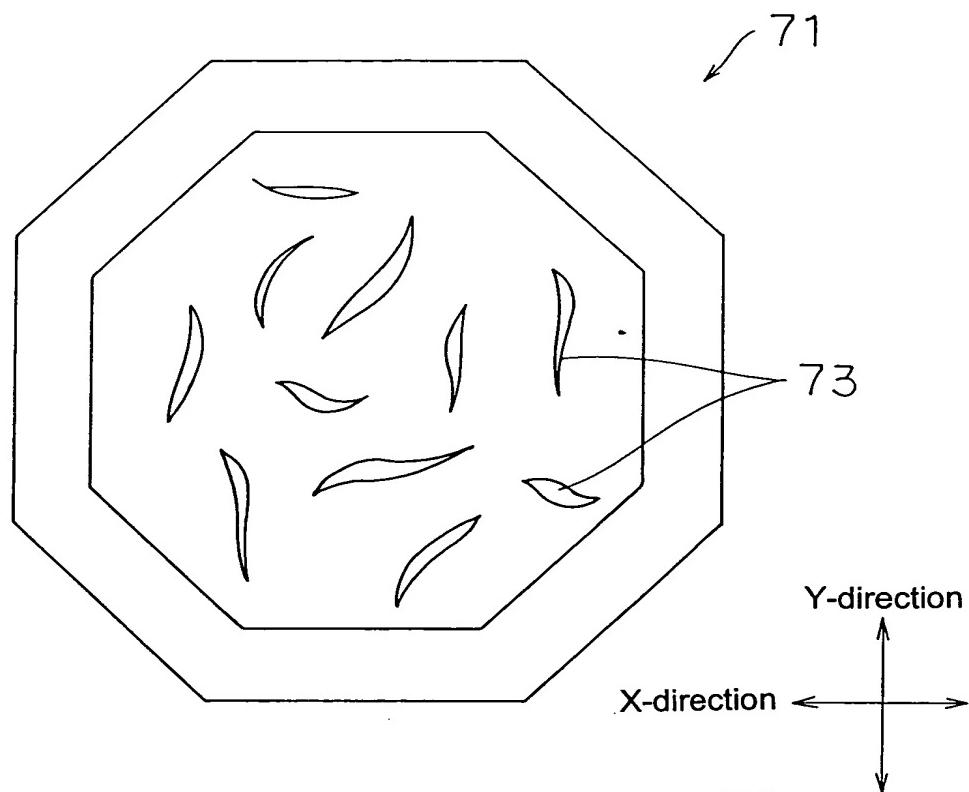
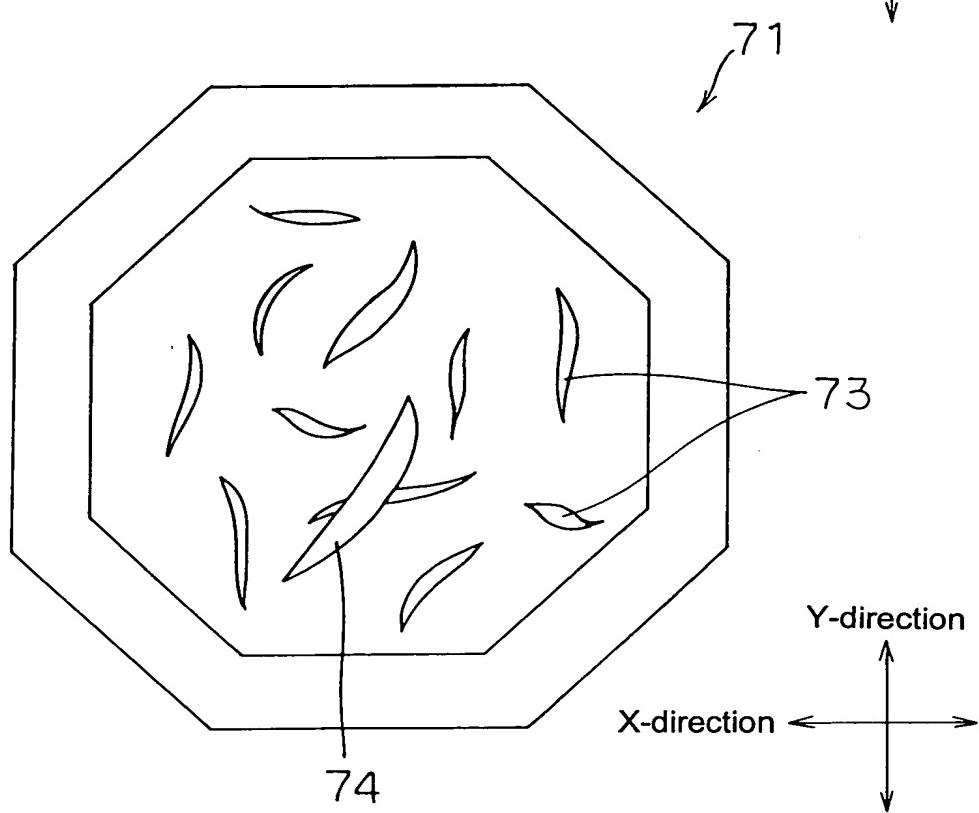


Fig.5b



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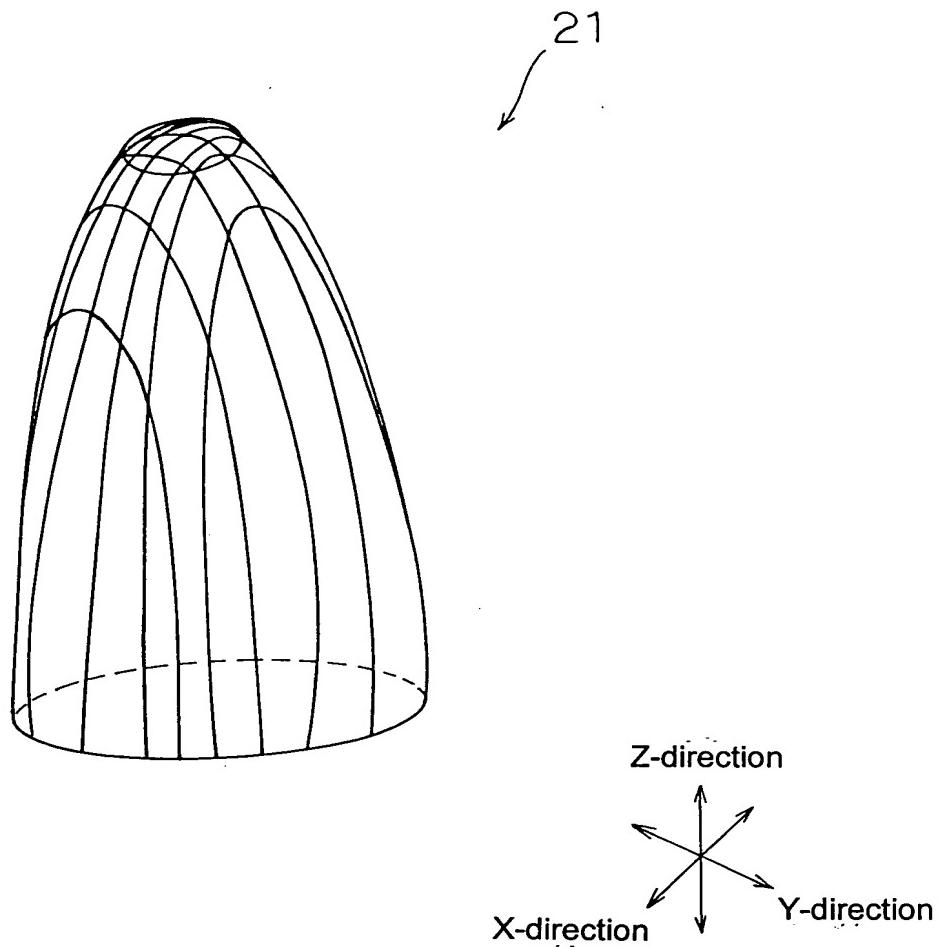


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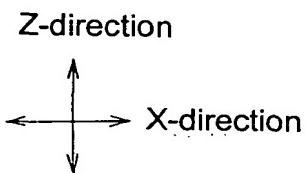


Fig. 7a



Fig. 7b

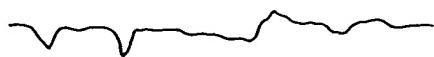


Fig. 7c



Fig. 7d



Fig. 7e

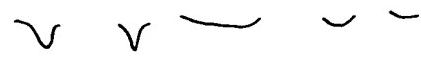


Fig. 7f

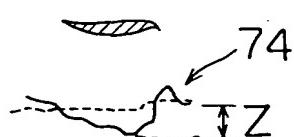


Fig. 7g

Fig. 8a

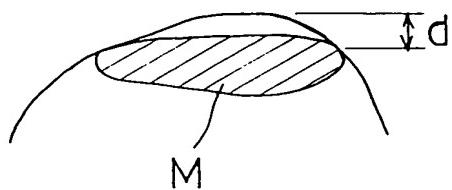


Fig. 8b

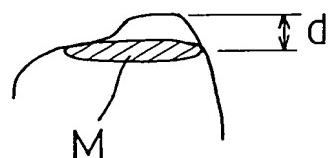


Fig. 9a

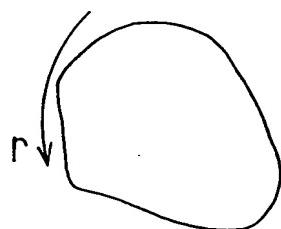


Fig. 9b

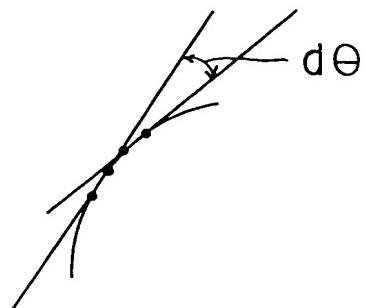
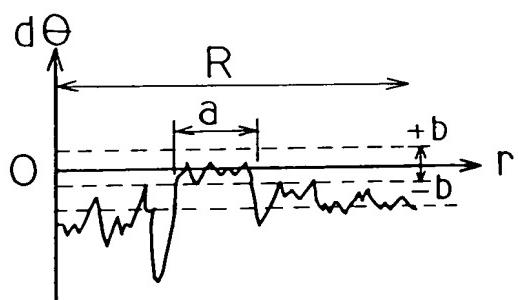


Fig. 9c



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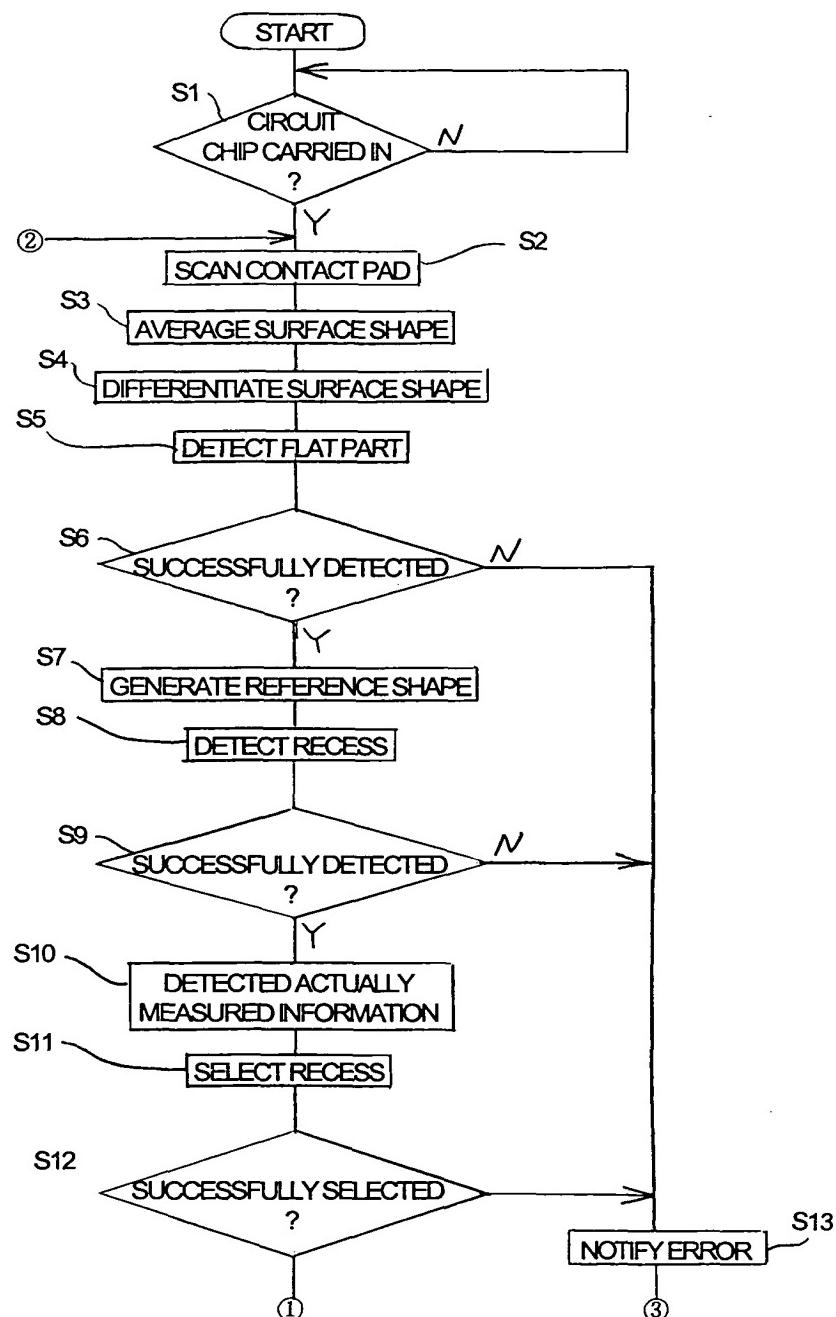


Fig.10

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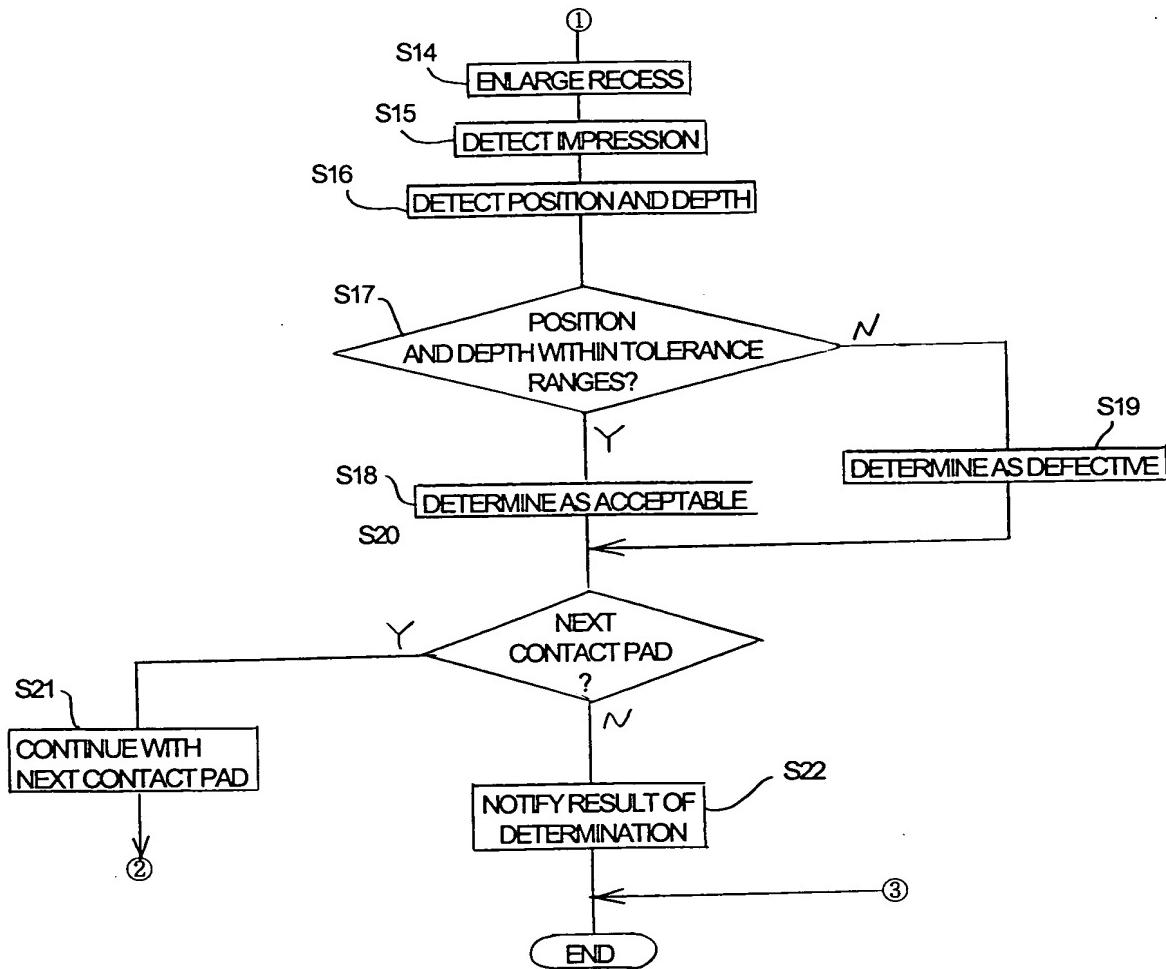


Fig.11

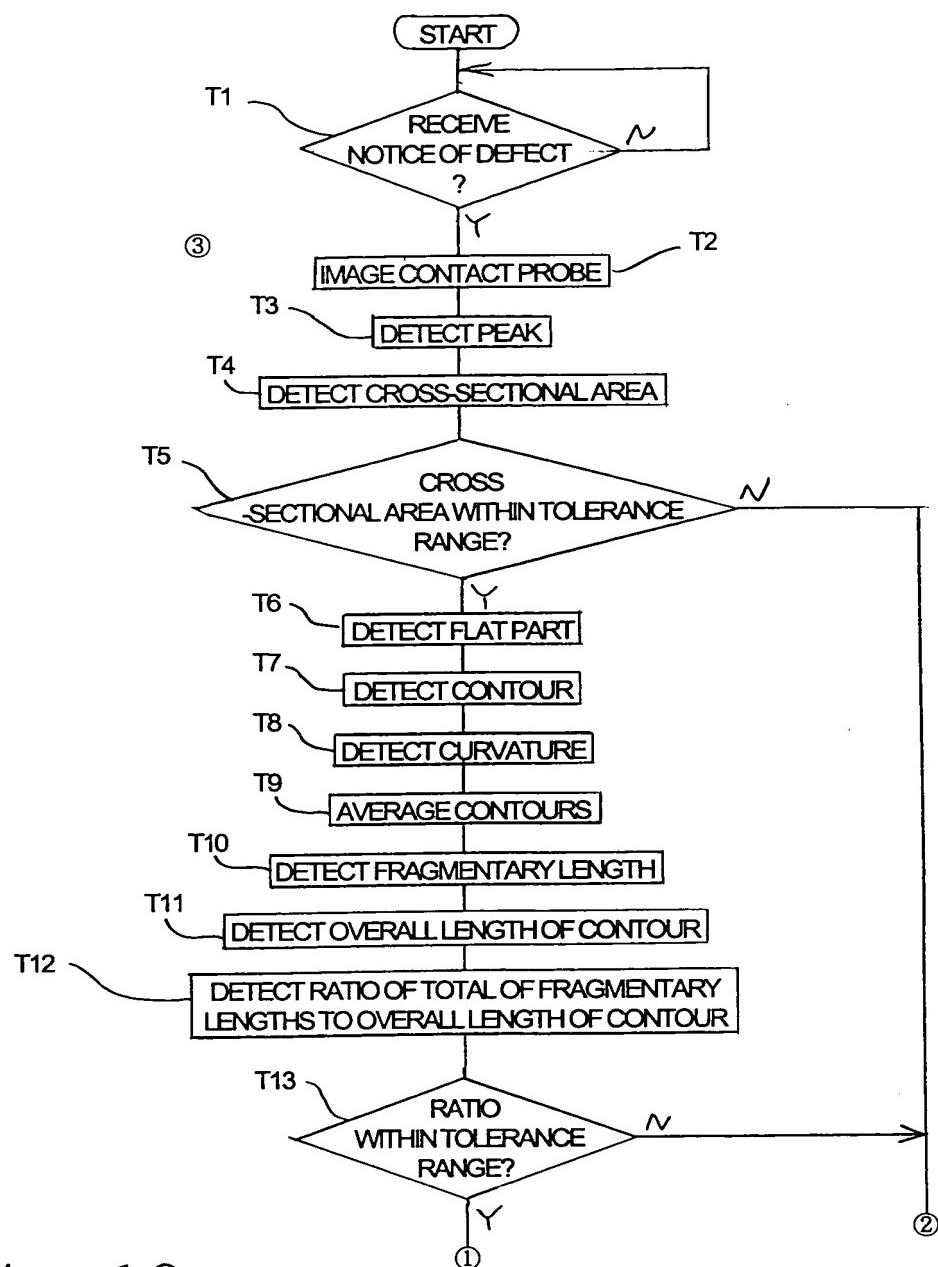


Fig.12

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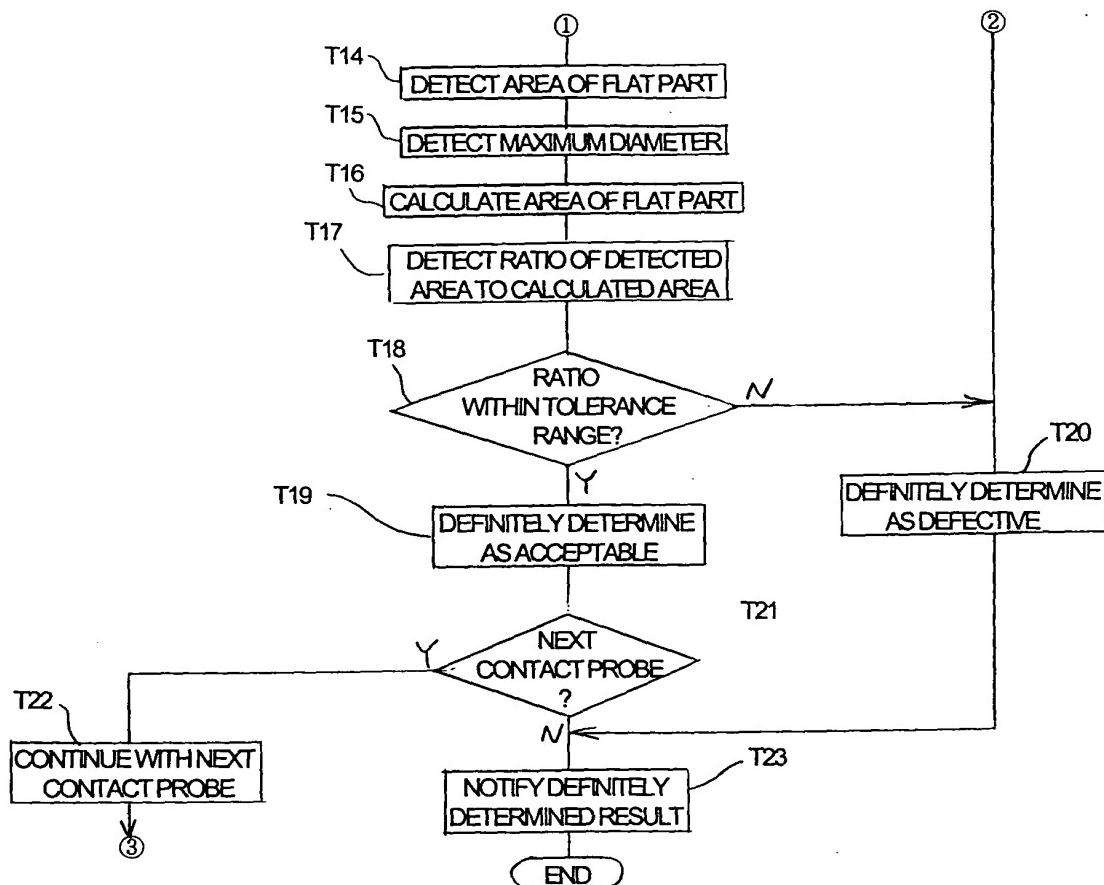


Fig.13